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In the Claims:

- 1-7. Cancelled
- 8. (Previously Presented) In a method of affecting cleaning to remove A1F₃ residue from walls of a reactor chamber, the method comprising the steps of:
- a) identifying cleaning process conditions of plasma containing H₂-gases that maximize H-atom concentration in said plasma of a gas mixture containing H₂ and Ar using optical emission spectroscopy or actinometry to identify the H atom concentration in the plasma based on the relative emission intensity from excited H and Ar atoms by the formula:

intensity of H ~ H atom concentration; intensity of Ar

said cleaning process conditions including one or more of flow rate, pressure, and RF power;

b) subjecting said reactor chamber in situ to a gas mixture of He/H2 for striking a plasma then subjecting said reactor chamber in situ to H2 gas according to the cleaning process conditions identified in step a) without opening said chamber and without shutting down said chamber to affect reduction and removal of said A1F3 residue.

9-25. Cancelled

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